The Speed of a Device Tester:
The Power of a Board Tester.

For circuit designs that are breaking down the old distinctions between devices and boards, Teradyne introduces a stunning test breakthrough. The L290 VLSI Module Test System.

The L290's device-tester performance, and its power to accurately test and diagnose large, complex circuits, define a totally new class of VLSI ATE.

1152 40 MHz Channels
Why compromise test speed for high pin count? Or vice versa? Only the L290 offers both.

New L290 test electronics deliver 40 MHz pattern rates to an unprecedented 1152 bidirectional channels. Interleaving pairs of channels boosts top test speed where needed, to a true 80 MHz.

To keep timing accurate, a proprietary deskew routine finely tunes each signal path's delay. And deskewing takes only \( \frac{1}{10} \) second per channel.

Flexibility to Match Your Design
Tight control over L290 signal timing lets you master exacting I/O specifications. With 250 ps resolution. Drive phases and detect windows can occur anywhere in a pattern cycle. So there's zero dead time.

As for program generation, the L290 is closely coupled with LASAR Version 6 simulation software for design and test. LASAR lets you take advantage of design verification.
through a circuit.

Or use a LASAR-generated fault dictionary to locate faults. The L290 records a module's failing test patterns in its data acquisition RAMs. Looks them up in the dictionary. And quickly reports the best matches.

Patterns. Measures test quality. And supplies the data needed for fault diagnosis.

The L290 is fully equipped for scan path designs. Serial pattern processors test shift paths efficiently. Each can source up to 16 million vectors to any L290 test channel.

Full analog and algorithmic memory test capabilities round out the L290's repertoire.

**Find Faults With or Without Probing**

Because faulty modules are too valuable to throw away, the L290 doesn't stop at pass/fail testing. Advanced diagnostics locate faults. With or without probing.

New guided probe technology analyzes nodal response at rates up to 80 MHz. Using dual threshold voltage comparison for accuracy, you can precisely measure both static and dynamic signal states as you trace back

**The Best of Both Worlds**

Today's modules need higher performance than any board tester has offered before. Higher speeds. Tighter timing.

So if your new designs need the speed and accuracy of a device tester, but the power of a board tester, consider the L290 VLSI Module Test System. It's ready now, for the technology leaders who need it.

To find out more, write Teradyne, 321 Harrison Avenue, Boston, MA 02118. Or call Daryl Layzer, L200 Product Group, 617/482-2700, ext. 2808.